



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : Confirmation No. 2449
Akira TERAOKA : Docket No. 2000-0311A
Serial No. 09/533,778 : Group Art Unit 2882
Filed March 24, 2000 : Examiner Pamela R. Hobden

X-RAY INSPECTION METHOD AND
APPARATUS USED FOR THE SAME

AMENDMENT

Assistant Commissioner for Patents,
Washington, D.C.

Sir:

In response to the Office Action of February 27, 2002, the period for response to which having been extended by one month to June 27, 2002, kindly amend the above-referenced U.S. patent application as follows:

IN THE SPECIFICATION AND ABSTRACT

Please replace the specification and abstract with the accompanying substitute specification and abstract. No new matter has been entered.

IN THE CLAIMS

Please cancel claims 1-20 without prejudice or disclaimer of the subject matter thereof, and substitute therefore the following new claims:

21.) A method of X-ray inspection of a section of a sample, comprising:
arranging an X-ray source and an X-ray detecting device so as to face each other with the sample between them;

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